

Search Notes



Application/Control No.

10/763,174

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

TANZAWA ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	100	02.09.05	Mr
	103	↓	↓
	102	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	02.09.05	Mr